

Notice of References Cited

Application/Control No.

10/595,434

Applicant(s)/Patent Under

Reexamination

KARG ET AL.

Examiner

JOEL G. HORNING

Art Unit

1712

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0063212	05-2002	Mirkin et al.	250/306
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Asahino et al (Physical Review Letters, Volume 86(2001), Number 19, pp 4334-4337).
	V	Takahashi et al (Ultramicroscopy, Volume 82 (2000), pp63-68).
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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